



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Shi-Chang Wooh
Serial No: 09/898,815
Filed: July 5, 2001
For: DEFECT DETECTION SYSTEM
AND METHOD

Group: 2878
Examiner: Yam, Stephen K.
Docket No: MIT-114J

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first class mail in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on December 9, 2003.

Olga Kadish
Olga Kadish

RESPONSE

This Response is in reply to the Office Action mailed October 15, 2003 in the subject application. In response to the Office Action, please consider the applicant's remarks as follows.

Remarks/Arguments begin on page 2 of this paper.